





Integrated Device Technology, Inc.  
2975 Stender Way, Santa Clara, CA - 95054

## PRODUCT/PROCESS CHANGE NOTICE (PCN) ADDENDUM

### PCN Summary

#### PCN Type:

Design Change  
Change to Fab Process

#### Commodity

Logic

#### Forecast or Execute

Execute

#### Planned or Unplanned

Unplanned

#### Data Sheet Change

No Change

### Detail of Change

For selected 3.3V Double Density Logic FCT products, IDT will be migrating to a new die revision for process consolidation. There is no data sheet specification or package change.

The affected part numbers are: 54/74FCT163344, 163501, 163827, 163646, 163244, 163245, 74FCT163373, 163374, 163543, 163601 and 163952

### Process / Design Changes

#### Current Die

#### Replacment Die

54/74FCT163344	54/74FCT163646
54/74FCT163501	54/74FCT163244
54/74FCT163827	54/74FCT163245
74FCT163543	74FCT163373
74FCT163601	74FCT163374
74FCT163952	

Wafer Fab Technology	CMOS 7	CMOS 7	CMOS 8
Feature Size	0.8 $\mu$ m	0.8 $\mu$ m	0.6 $\mu$ m
Minimum Gate Oxide	140 Å	140 Å	140 Å
Wafer Size	6"	6"	6"
Die Dimension (sq mils)	11.4	6.28	7.76
Fab Facility	Fab 2	Fab 2	Fab 2
Datecode Prefix Designator	N	L	X

### Conversion schedule (Estimated)

PCN # L9910-03R1

#### Sample Availability

#### Production Shipments

54/74FCT163344	Available
54/74FCT163501	Available

February 1, 2000	February 1, 2000
February 1, 2000	



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54/74FCT163646	Available	February 1, 2000
54/74FCT163827	Available	February 1, 2000
54/74FCT163244	Available	February 1, 2000
54/74FCT163245	Available	February 1, 2000
74FCT163373	Available	June 22, 2000
74FCT163374	Available	June 22, 2000
74FCT163543	Available	June 22, 2000
74FCT163601	Available	June 22, 2000
74FCT163952	Available	June 22, 2000

### Qualification Data

**Test Vehicle:** 65501X/65373X/65244X/65646X

	Lot #1	Lot #2	Lot #3
Operating Life Test (Dynamic) (1000 Hrs @ 125°C, Vcc = 3.3V)	116/0	116/0	116/0
Temperature cycling (-65°C to +150°C, 500cyc)	45/0	45/0	45/0
Bake and Ball Shear Test	20/0	20/0	20/0
Die Shear Test	3/0	3/0	3/0
ESD: HMB Category II (>2kV) Mil-Std 883, Method 3015	3/0	3/0	3/0
ESD: CDM	3/0	3/0	3/0
Latch-up JEDEC Std 17	10/0	N/A	N/A
Electrical characterization	10/0	N/A	N/A
I/O capacitance	5/0	N/A	N/A

### Characterization Data:

Characterization Data is available upon request.